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	APPLICANT(s) Hans W. P. KOOPS et al.	
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U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME
AZ	**US 5,263,043	November 16, 1993	John Walsh
AZ	**US 3,586,899	June 22, 1971	Harold Fleisher
AZ	**US 5,268,693	December 7, 1993	John Walsh
AZ	**US 4,727,550	February 23, 1988	Chang et al.

**Cited on German Patent Office Search Report (copy of reference and search report enclosed).

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
				YES	NO
AZ	WO 98/21788	May 22, 1998	PCT	X*	
AZ	WO 87/01873	March 26, 1987	PCT	X*	
AZ	DE 196 09 234	September 11, 1997	Fed. Rep. of Germany	X**	
AZ	WO 98/21788	May 22, 1998	PCT	X**	

*Copy of reference is not enclosed because reference is cited and described in International Search Report (copy of reference provided by International Searching Authority).

**Cited on German Patent Office Search Report (copy of reference and corresponding English abstract and search report enclosed).

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
AZ	*Schoessler C et al., "Nanostructured integrated electron source", Silicon Heterostructures: From Physics to Devices, Barga, Italy, Sept 16-19, 1997, vol. 16, no. 2, pages 862-865, Journal of Vacuum Science & Technology (Microelectronics and Nanometer Structures), March-April 1998, AIP for American Vacuum Soc. USA.
AZ	**JP 0004199885, Abstracts of Japan, Mitsubishi Electric Corp., "Semiconductor Light Emitting Device", July 21, 1992.

*Copy of reference is not enclosed because reference is cited and described in International Search Report (copy of reference provided by International Searching Authority).

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EXAMINER AZ	DATE CONSIDERED 9/28/03
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